GA10SICP12-247

Silicon Carbide Junction Transistor/Schottky Diode Co-pack

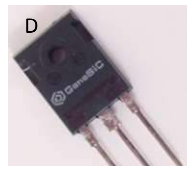
V_{DS}	=	1200 V
$R_{DS(ON)}$	=	120 mΩ
$I_{D\ (Tc\ =\ 25°C)}$	=	25 A
$h_{FE\ (Tc\ =\ 25°C)}$		100

Features

- 175°C Maximum Operating Temperature
- Gate Oxide free SiC switch
- Exceptional Safe Operating Area
- Integrated SiC Schottky Rectifier
- Excellent Gain Linearity
- Temperature Independent Switching Performance
- Low output capacitance
- Positive temperature co-efficient of $R_{DS,ON}$
- Suitable for connecting an anti-parallel diode

Package

- RoHS Compliant



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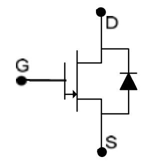

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Advantages

- Compatible with Si MOSFET/IGBT Gate Drive ICs
- > 20 µs Short-Circuit Withstand Capability
- Lowest-in-class Conduction Losses
- High Circuit Efficiency
- Minimal Input Signal distortion
- High Amplifier Bandwidth
- Reduced cooling requirements
- Reduced system size

Applications

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

Maximum Ratings at T_j = 175 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit
SiC Junction Transistor				
Drain – Source Voltage	V_{DS}	V_{GS} = 0 V	1200	V
Continuous Drain Current	I_D	$T_{C,MAX}$ = 95 °C	10	A
Gate Peak Current	I_{GM}		10	A
Turn-Off Safe Operating Area	RBSOA	T_{VJ} = 175 °C, I_G = 1 A, Clamped Inductive Load	$I_{D,max}$ = 10 @ $V_{DS} \le V_{DSmax}$	A
Short Circuit Safe Operating Area	SCSOA	T_{VJ} = 175 °C, I_G = 1 A, V_{DS} = 800 V, Non Repetitive	20	µs
Reverse Gate – Source Voltage	V_{SG}		30	V
Reverse Drain – Source Voltage	V_{SD}		25	V
Power Dissipation	P_{tot}	T_C = 95 °C	91	W
Storage Temperature	T_{stg}		-55 to 175	°C
Free-wheeling Silicon Carbide diode				
DC-Forward Current	I_F	$T_C \le$ 150 °C	10	A
Non Repetitive Peak Forward Current	I_{FM}	T_C = 25 °C, t_P = 10 µs	280	A
Surge Non Repetitive Forward Current	$I_{F,SM}$	t_P = 10 ms, half sine, T_C = 25 °C	65	A

Thermal Characteristics

Thermal resistance, junction - case	R_{thJC}	SiC Junction Transistor	0.88	°C/W
Thermal resistance, junction - case	R_{thJC}	SiC Diode	0.85	°C/W

Mechanical Properties

Mounting torque	M		0.6	Nm

Electrical Characteristics at T_j = 175 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values min.	Values typ.	Values max.	Unit
SJT On-State Characteristics						
Drain – Source On Resistance	$R_{DS(ON)}$	I_D = 10 A, I_G = 200 mA, T_j = 25 °C I_D = 10 A, I_G = 400 mA, T_j = 125 °C I_D = 10 A, I_G = 800 mA, T_j = 175 °C		120 150 220		mΩ
Gate Forward Voltage	$V_{GS(FWD)}$	I_G = 500 mA, T_j = 25 °C I_G = 500 mA, T_j = 175 °C		3.3 3.1		V
DC Current Gain	h_{FE}	V_{DS} = 5 V, I_D = 10 A, T_j = 25 °C V_{DS} = 5 V, I_D = 10 A, T_j = 175 °C		100 TBD		
SJT Off-State Characteristics						
Drain Leakage Current	I_{DSS}	V_R = 1200 V, V_{GS} = 0 V, T_j = 25 °C V_R = 1200 V, V_{GS} = 0 V, T_j = 125 °C V_R = 1200 V, V_{GS} = 0 V, T_j = 175 °C		350 530 700		nA
Gate Leakage Current	I_{SG}	V_{SG} = 20 V, T_j = 25 °C		20		nA
SJT Capacitance Characteristics						
Input Capacitance	C_{iss}	V_{GS} = 0 V, V_D = 1 V, f = 1 MHz		tbd		pF
Reverse Transfer/Output Capacitance	C_{rss}/C_{oss}	V_D = 1 V, f = 1 MHz		tbd		pF
SJT Switching Characteristics						
Turn On Delay Time	$t_{d(on)}$	V_{DD} = 800 V, I_D = 10 A, $R_{G(on)}$ = $R_{G(off)}$ = tbd Ω, FWD = GB10SLT12, T_j = 25 °C Refer to Figure 15 for gate current waveform		tbd		ns
Rise Time	t_r			tbd		ns
Turn Off Delay Time	$t_{d(off)}$			tbd		ns
Fall Time	t_f			tbd		ns
Turn-On Energy Per Pulse	E_{on}			tbd		µJ
Turn-Off Energy Per Pulse	E_{off}			tbd		µJ
Total Switching Energy	E_{ts}			tbd		µJ
Turn On Delay Time	$t_{d(on)}$	V_{DD} = 800 V, I_D = 10 A, $R_{G(on)}$ = $R_{G(off)}$ = tbd Ω, FWD = GB10SLT12, T_j = 175 °C Refer to Figure 15 for gate current waveform		tbd		
Rise Time	t_r			tbd		ns
Turn Off Delay Time	$t_{d(off)}$			tbd		ns
Fall Time	t_f			tbd		ns
Turn-On Energy Per Pulse	E_{on}			tbd		µJ
Turn-Off Energy Per Pulse	E_{off}			tbd		µJ
Total Switching Energy	E_{ts}			tbd		µJ
Free-wheeling Silicon Carbide Schottky Diode						
Forward Voltage	V_F	I_F = 10 A, V_{GE} = 0 V, T_j = 25 °C (175 °C)		1.55		V
Diode Knee Voltage	$V_{D(knee)}$	T_j = 25 °C, I_F = 1 mA		0.8		V
Peak Reverse Recovery Current	I_{rrm}	I_F = 10 A, V_{GE} = 0 V, V_R = 800 V, $-dI_F/dt$ = 625 A/µs, T_j = 175 °C		tbd		A
Reverse Recovery Time	t_{rr}			tbd		ns
Rise Time	t_r	V_{DD}= 800 V, I_D = 10 A, R_{gon} = R_{goff} = tbd Ω, T_j= 25 °C		tbd		ns
Fall Time	t_f			tbd		ns
Turn-On Energy Loss Per Pulse	E_{on}			tbd		µJ
Turn-Off Energy Loss Per Pulse	E_{off}			tbd		µJ
Reverse Recovery Charge	Q_{rr}			tbd		nC
Rise Time	t_r	V_{DD}= 800 V, I_D = 10 A, R_{gon} = R_{goff} = tbd Ω, T_j= 175 °C		tbd		ns
Fall Time	t_f			tbd		ns
Turn-On Energy Loss Per Pulse	E_{on}			tbd		µJ
Turn-Off Energy Loss Per Pulse	E_{off}			tbd		µJ
Reverse Recovery Charge	Q_{rr}			tbd		nC

Figures

TBD

Figure 1: Typical Output Characteristics at 25 °C

TBD

Figure 2: Typical Output Characteristics at 125 °C

TBD

Figure 3: Typical Output Characteristics at 175 °C

TBD

Figure 4: Typical Gate Source I-V Characteristics vs. Temperature

TBD

Figure 5: Normalized On-Resistance and Current Gain vs. Temperature

TBD

Figure 6: Typical Blocking Characteristics

TBD

Figure 7: Capacitance Characteristics

TBD

Figure 8: Capacitance Characteristics

TBD

Figure 9: Typical Hard-switched Turn On Waveforms

TBD

Figure 10: Typical Hard-switched Turn Off Waveforms

TBD

Figure 11: Typical Turn On Energy Losses and Switching Times vs. Temperature

TBD

Figure 12: Typical Turn Off Energy Losses and Switching Times vs. Temperature

TBD

TBD

Figure 13: Typical Turn On Energy Losses vs. Drain Current

Figure 14: Typical Turn Off Energy Losses vs. Drain Current

TBD

TBD

Figure 15: Typical Gate Current Waveform

Figure 16: Typical Hard Switched Device Power Loss vs. Switching Frequency [1]

TBD

TBD

Figure 17: Power Derating Curve

Figure 18: Forward Bias Safe Operating Area

[1] – Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.

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Figure 19: Turn-Off Safe Operating Area

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Figure 20: Transient Thermal Impedance

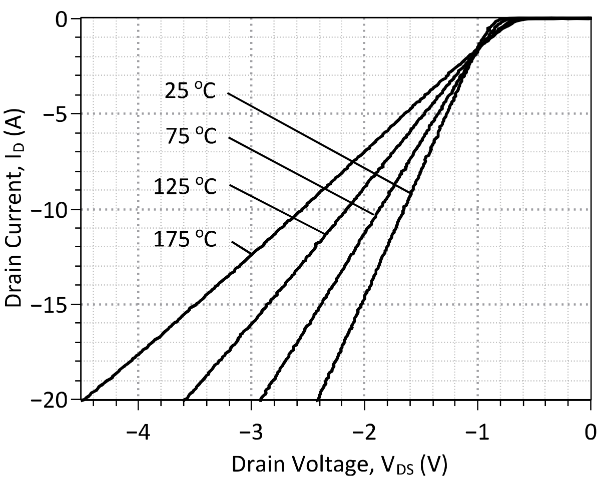


Figure 21: Typical FWD Forward Characteristics

Gate Drive Theory of Operation for the GA10SICP12-263

The SJT transistor is a current controlled transistor which requires a positive gate current for turn-on as well as to remain in on-state. An ideal gate current waveform for ultra-fast switching of the SJT, while maintaining low gate drive losses, is shown in Figure 22.

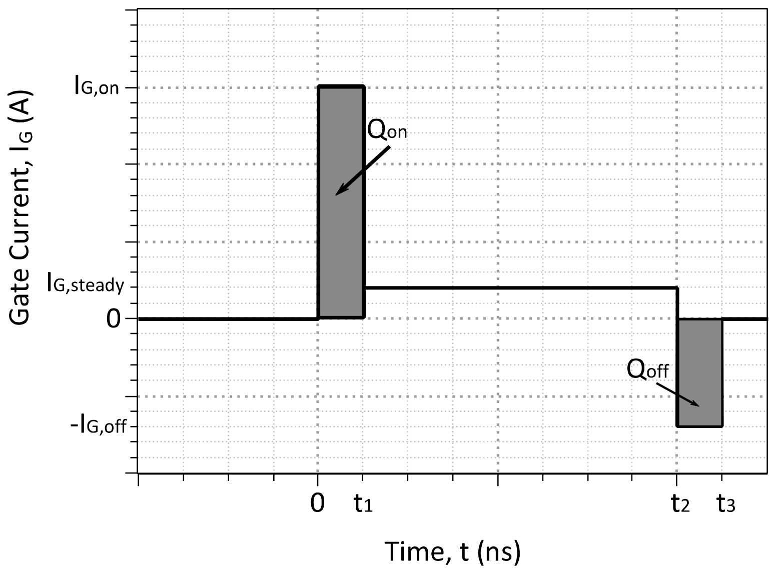


Figure 22: Idealized Gate Current Waveform

Gate Currents, $I_{G,pk}$/-$I_{G,pk}$ and Voltages during Turn-On and Turn-Off

An SJT is rapidly switched from its blocking state to on-state, when the necessary gate charge, Q_G, for turn-on is supplied by a burst of high gate current, $I_{G,on}$, until the gate-source capacitance, C_{GS}, and gate-drain capacitance, C_{GD}, are fully charged.

$$I_{G,on} * t_1 \geq Q_{gs} + Q_{gd}$$

The $I_{G,pon}$ pulse should ideally terminate, when the drain voltage falls to its on-state value, in order to avoid unnecessary drive losses during the steady on-state. In practice, the rise time of the $I_{G,on}$ pulse is affected by the parasitic inductances, L_{par} in the module and drive circuit. A voltage developed across the parasitic inductance in the source path, L_s, can de-bias the gate-source junction, when high drain currents begin to flow through the device. The applied gate voltage should be maintained high enough, above the $V_{GS,ON}$ level to counter these effects.

A high negative peak current, $-I_{G,off}$ is recommended at the start of the turn-off transition, in order to rapidly sweep out the injected carriers from the gate, and achieve rapid turn-off. While satisfactory turn off can be achieved with V_{GS} = 0 V, a negative gate voltage V_{GS} may be used in order to speed up the turn-off transition.

Steady On-State

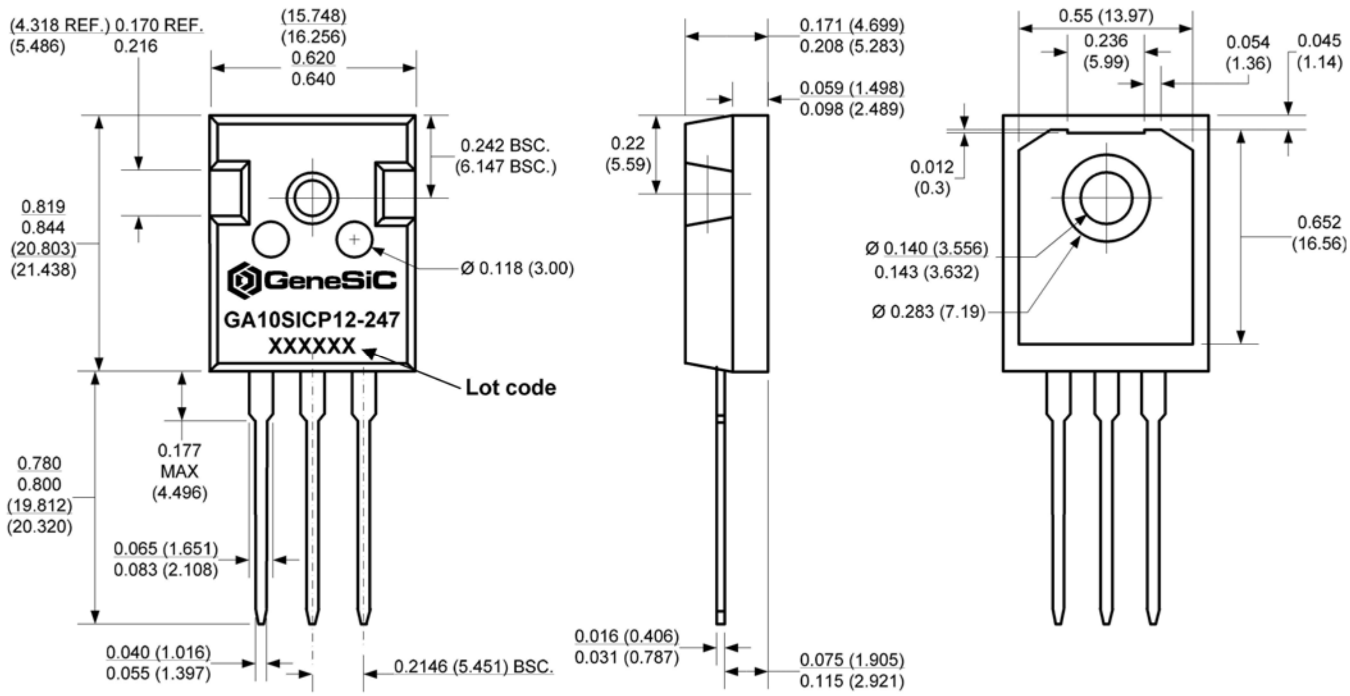
After the device is turned on, I_G may be advantageously lowered to $I_{G,steady}$ for reducing unnecessary gate drive losses. The $I_{G,steady}$ is determined by noting the DC current gain, h_{FE}, of the device

The desired $I_{G,steady}$ is determined by the peak device junction temperature T_J during operation, drain current I_D, DC current gain h_{FE}, and a 50 % safety margin to ensure operating the device in the saturation region with low on-state voltage drop by the equation:

$$I_{G,steady} \approx \frac{I_D}{h_{FE}(T, I_D)} * 1.5$$

Package Dimensions:

TO-247AB **PACKAGE OUTLINE**



NOTE
1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History			
Date	Revision	Comments	Supersedes
2014/08/25	1	Gate Drive Theory Update	
2013/09/12	0	Initial release	

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